

Advanced Burn-In & Test System

A high capacity system for test and burn-in of high power devices using sockets with independent temperature control



ABTS iSocket BIB



ABTS VTR BIB



System Benefits:

- High Power Burn-in
 - ◆ Test and burn-in of devices up to 70W
 - ◆ Individual device temperature control (ITC) using iSocket* or VTR technology
 - ◆ System can also be used for test and burn-in of low power devices that do not require ITC
- True Per-pin Tester Architecture
 - ◆ 256 I/O channels
 - ◆ Per-pin voltage, timing, formatting and tri-state on-the-fly
 - ◆ 10MHz data rate, 20MHz clocks
 - ◆ Pattern Generator & Driver per slot
- Very High System Capacity
 - ◆ Up to 36 burn-in board slots
 - ◆ Up to 42 devices per burn-in board with ITC, more without
 - ◆ 36KW chamber dissipation
 - ◆ Small system footprint
 - ◆ No side access required
- Low Cost of Ownership
 - ◆ Cost effective burn-in boards (only edge fingers, no costly connectors, cost effective size)
 - ◆ Highly efficient power delivery

“Changing the Way ICs Are Tested”

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